

# Performance

## Throughput of 5000E

A six test step MOSFET test program (VGSTH, BVDSS, RDSON, 2 VGSON, and GFS calculation) takes approximately 96 milliseconds to run and provides a throughput of up to 37,440 devices per hour.

## Standard Features

- 50A / 1KV Standard
- 100A Optional
- 2KV Optional
- 99 Tests (256 Tests Optional)
- 96 Sorts
- Branching
- Handler Interface
- Programmable Relay Drivers
- Auto Calibration\*
- Self Test\*
- Data Management\*
- Can be linked with other test equipment using LabView® or other similar software
- Wafer Map Option

\*See pages 8, 9, and 10 of *5300 Series Buyer's Guide*

## Test Methods

The Model 5000E incorporates single test measure techniques to assure a measured value with only one application of stimulus, including tests such as hFE. This minimizes test time, minimizes internal device heating and maximizes throughput.

**High resolution assures tests like RDSON to an accuracy of  $\pm 0.5$  milliohm at 1 A test current.**

## Adaptors

|                             |  |
|-----------------------------|--|
| Scanner:                    | ADP401 A-8/16<br>8 or 16 Pin Programmable Matrix   |
| Multiplex:                  | MUX-3S/4S: 3 or 4 Output Multiplexer   |
| Fixtures / Device Adaptors: | A selection of fixtures and adaptors are available for surface mount and other leaded packages** |

\*\*See pages 11, 12, and 14 of *5300 Series Buyer's Guide*

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